

TEST REPORT

Applicant: SEUIC Technologies Co., Ltd.
Address: NO.15 Xinghuo Road, Nanjing New & High
Technology Industry Development Zone, 210061,
Nanjing City, Jiangsu Province, China
Equipment Type: RFID Reader (ADPM)
Model Name: AUTOID UF40 (refer to section 2.3)
Brand Name: Seuic
FCC ID: 2AC68-AUTOIDUF40
Test Standard: 47 CFR Part 15 Subpart B
ANSI C63.4-2014
Sample Arrival Date: Jul. 10, 2025
Test Date: Jul. 15, 2025- Jul. 22, 2025
Date of Issue: Aug. 25, 2025

ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.

Tested by: Qiu Yongjing**Checked by:** Zong Liyao**Approved by:** Tolan Tu
(Technical Director)

Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Aug. 25, 2025</u>	<u>Initial Issue</u>

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1 GENERAL INFORMATION

1.1 Test Laboratory

Name	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1/F, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6685 0100

1.2 Test Location

Name	Shenzhen BALUN Technology Co., Ltd.
Location	☒ Block B, 1/F, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
	☐ 1/F, Building B, Ganghongji High-tech Intelligent Industrial Park, No. 1008, Songbai Road, Yangguang Community, Xili Sub-district, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Accreditation Certificate	The laboratory is a testing organization accredited by FCC as a accredited testing laboratory. The designation number is CN1196. The certification body is American Association for Laboratory Accreditation (A2LA).

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	SEUIC Technologies Co., Ltd.
Address	NO.15 Xinghuo Road, Nanjing New & High Technology Industry Development Zone, 210061, Nanjing City, Jiangsu Province, China

2.2 Manufacturer Information

Manufacturer	SEUIC Technologies Co., Ltd.
Address	NO.15 Xinghuo Road, Nanjing New & High Technology Industry Development Zone, 210061, Nanjing City, Jiangsu Province, China

2.3 General Description for Equipment under Test (EUT)

EUT Name	RFID Reader (ADPM)
Model Name Under Test	AUTOID UF40
Series Model Name	AUTOID UF20, AUTOID UF30, AUTOID UF50
Description of Model name differentiation	All models are same with electrical parameters and internal circuit structure, but only differ in model names and the colours of the appearance. (this information provided by the applicant)
Hardware Version	1.0.0.5
Software Version	1.0.0.121
Dimensions (Approx.)	N/A
Weight (Approx.)	N/A

2.4 Ancillary Equipment

Ancillary Equipment 1	Adapter	
	Brand Name	N/A
	Model No.	FX65C-240200Z
	Serial No.	N/A
	Rated Input	100-240V~, 50/60Hz, 1500mA
	Rated Output	24.0V= 2.0A

2.5 Technical Information

Network and Wireless connectivity	2.4G WIFI 802.11b, 802.11g, 802.11n(HT20/40) 5G WIFI 802.11a, 802.11n(HT20/40), 802.11ac(VHT20/40/80) RFID
Classification of equipment	Class B
The highest internal frequency of EUT	5850 MHz

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	47 CFR Part 15 Subpart B	Unintentional Radiators
2	ANSI C63.4-2014	American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Remark
1	Radiated Emission	15.109	Pass	--
2	Conducted Emission, AC Ports	15.107	Pass	--

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=2$.

Measurement	Value
Conducted emissions (9 kHz-30 MHz)	3.2 dB
Radiated emissions (30 MHz-1 GHz)-966#2	4.4 dB
Radiated emissions (1 GHz-18 GHz)-966#2	5.0 dB

4 GENERAL TEST CONFIGURATIONS

4.1 Test Enclosure List

Description	Manufacturer	Model	Serial No.	Length	Description	Use
Laptop	N/A	N/A	N/A	N/A	N/A	☒
USB drive	N/A	N/A	N/A	N/A	N/A	☒
RS232 to USB Cable	N/A	N/A	N/A	N/A	N/A	☒
RF ID Antenna	N/A	N/A	N/A	N/A	N/A	☒
RF Cable	N/A	N/A	N/A	N/A	N/A	☒
POE Adapter	N/A	N/A	N/A	N/A	N/A	☒

4.2 Test Configurations

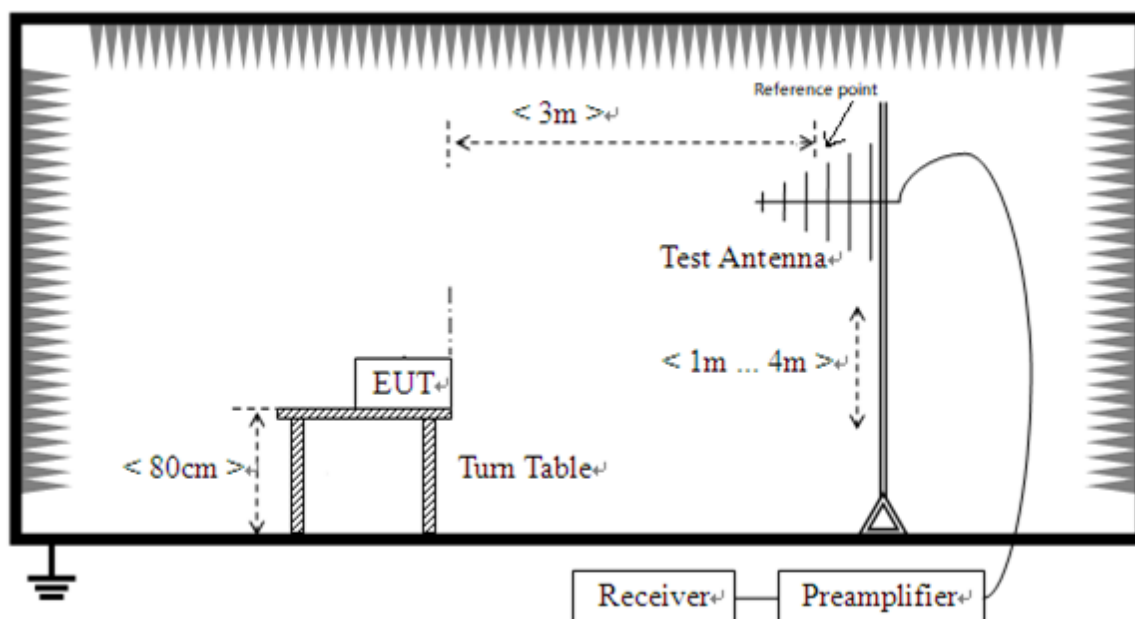
All test modes of EUT are listed in the table below.

Test Mode Configuration	Description
Mode 1	<u>The Standby Test Mode</u> EUT + Antenna + USB drive + Adapter + RS232 Cable + Laptop + RJ45 Cable + RF Cable + RF ID Antenna
Mode 2	<u>The Normal Operating Test Mode</u> EUT + Antenna + USB drive + Adapter + RS232 Cable + Laptop + RJ45 Cable + RF Cable + RF ID Antenna
Mode 3	<u>The Normal Operating Test Mode</u> EUT + Antenna + USB drive + POE Adapter + RS232 Cable + Laptop + RJ45 Cable + RF Cable + RF ID Antenna

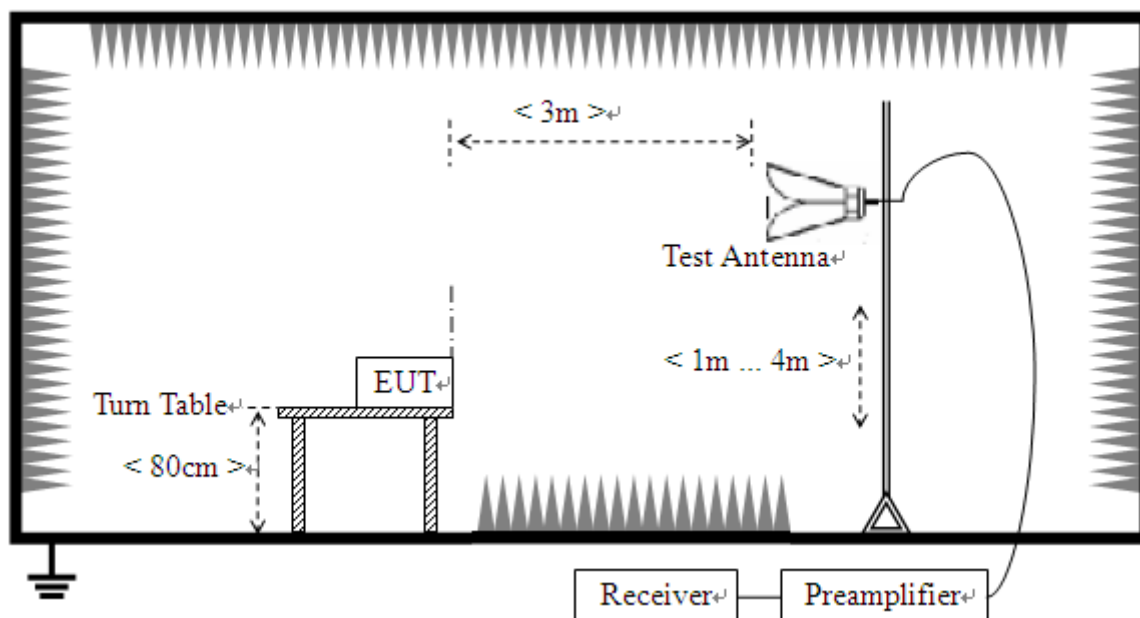
Test Case	Test Mode Configuration	Worst Mode
Radiated Emission	Mode 1~Mode 3	2
Conducted Emission, AC Ports	Mode 1~Mode 3	2
Note: All operation modes were tested, but only test data of the worst mode was presented in this report.		

4.3 Test Setups

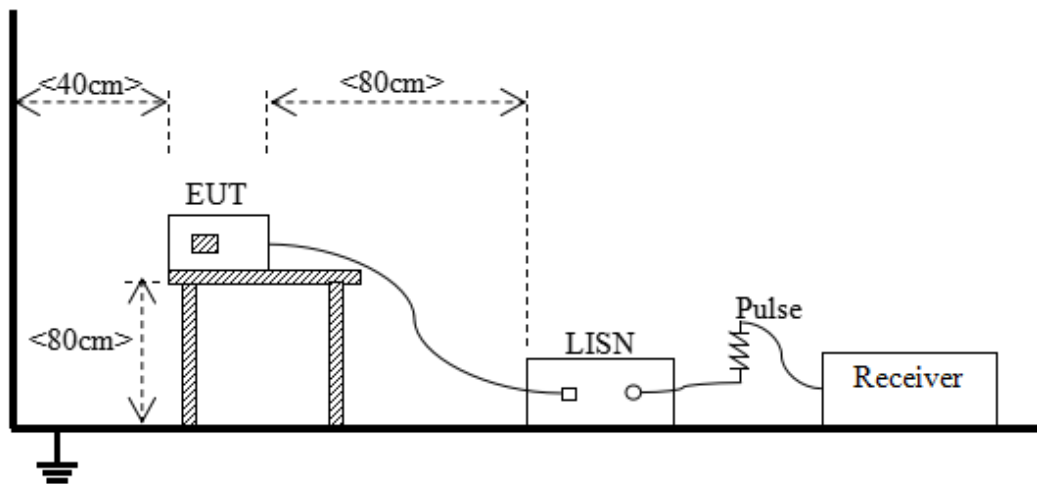
Test Setup 1



Radiated Emission (30 MHz-1 GHz)



Radiated Emission (above 1 GHz)

Test Setup 2

Conducted Emissions, AC Ports

5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range (MHz)	Class B (at 3 m)		Class A (at 3 m)
	Field Strength ($\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)
30 - 88	100	40	49.5
88 - 216	150	43.5	54
216 - 960	200	46	56.9
Above 960	500	54	60

NOTE:

- 1) Field Strength (dB $\mu\text{V/m}$) = $20 \cdot \log [\text{Field Strength } (\mu\text{V/m})]$.
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For 30 MHz to 1000 MHz, the CISPR quasi-peak is employed.

For above 1000 MHz, according to the requirements of FCC 15.35, unless otherwise specified, the limit on peak radio frequency emissions is 20 dB above the maximum permitted average emission limit applicable to the equipment under test.

Frequency range (GHz)	Class B (at 3 m)			Class A (at 3 m)	
	Field Strength ($\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)
1 - F_M	500	54	74	60	80

Note 1: The highest measurement frequency, F_M , in GHz, shall be determined as next Table.

Note 2: Average Class A limit at 3m L_{3m} is determined by the following conversion formula:

$$L_{3m} = L_{10m} + 20 \cdot \log(d_{10m}/d_{3m})$$

Where:

L_{3m} is Average Class A limit at 3m;

L_{10m} is Average Class A limit at 10m;

d_{10m} is Measurement distance in 10m;

d_{3m} is Measurement distance in 3m.

For this case: $L_{3m} = 49.5 + 20 \cdot \log(10/3) = 60$ (dB $\mu\text{V/m}$).

Highest internal frequency (F_X)	Highest measurement frequency (F_M)
$F_X \leq 108 \text{ MHz}$	1 GHz
$108 \text{ MHz} \leq F_X \leq 500 \text{ MHz}$	2 GHz
$500 \text{ MHz} \leq F_X \leq 1 \text{ GHz}$	5 GHz
$F_X \geq 1 \text{ GHz}$	$5 * F_X$ or 40 GHz, whichever is lower.
Note: F_X is Highest frequency generated or used in the device or on which the device operates or tunes.	

5.1.1.2 Test Setup

Refer to 4.3 section (test setup 1) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Radiated Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

The measurement frequency range is from 30 MHz to the 5th harmonic of the maximum frequency of the EUT internal source. The Turn Table is actuated to turn from 0° to 360°, and both horizontal and vertical polarizations of the Test Antenna are used to find the maximum radiated power. Mid channels on all channel bandwidth verified. Only the worst RB size/offset presented.

Use the following spectrum analyzer settings:

Span = wide enough to fully capture the emission being measured

RBW = 1 MHz for $f \geq 1 \text{ GHz}$, 100 kHz for $f < 1 \text{ GHz}$

VBW $\geq$ RBW

Sweep = auto

Detector function = peak for $f < 1 \text{ GHz}$, peak & RMS Average for $f \geq 1 \text{ GHz}$

Trace = max hold

5.1.1.4 Test Result and Test Equipment List

Please refer to ANNEX A.1.

NOTE:

1. Results (dB μ V/m) = Reading (dB μ V) + Factor (dB/m)

The reading level is calculated by software which is not shown in the sheet

2. Factor (dB/m) = Antenna Factor (dB/m) + Cable Factor (dB) – Amplifier Gain (dB)

3. Margin = Limit - Results

5.1.2 Conducted Emission, AC Ports

5.1.2.1 Test Limit

Frequency range (MHz)	Class A	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	79	66
0.50 - 30	73	60

Frequency range (MHz)	Class B	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.3 section test (test setup 2) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

Use the following spectrum analyzer settings:

RBW = 9 kHz

VBW $\geq$ RBW

Sweep = 10ms

Detector function = peak & Average

Trace = max hold

5.1.2.4 Test Result and Test Equipment List

Please refer to ANNEX A.2.

NOTE:

1. Results (dB μ V) = Reading (dB μ V) + Factor (dB)

The reading level is calculated by software which is not shown in the sheet

2. Factor = Insertion loss + Cable loss

3. Margin = Limit - Results

ANNEX A TEST RESULTS

A.1 Radiated Emission

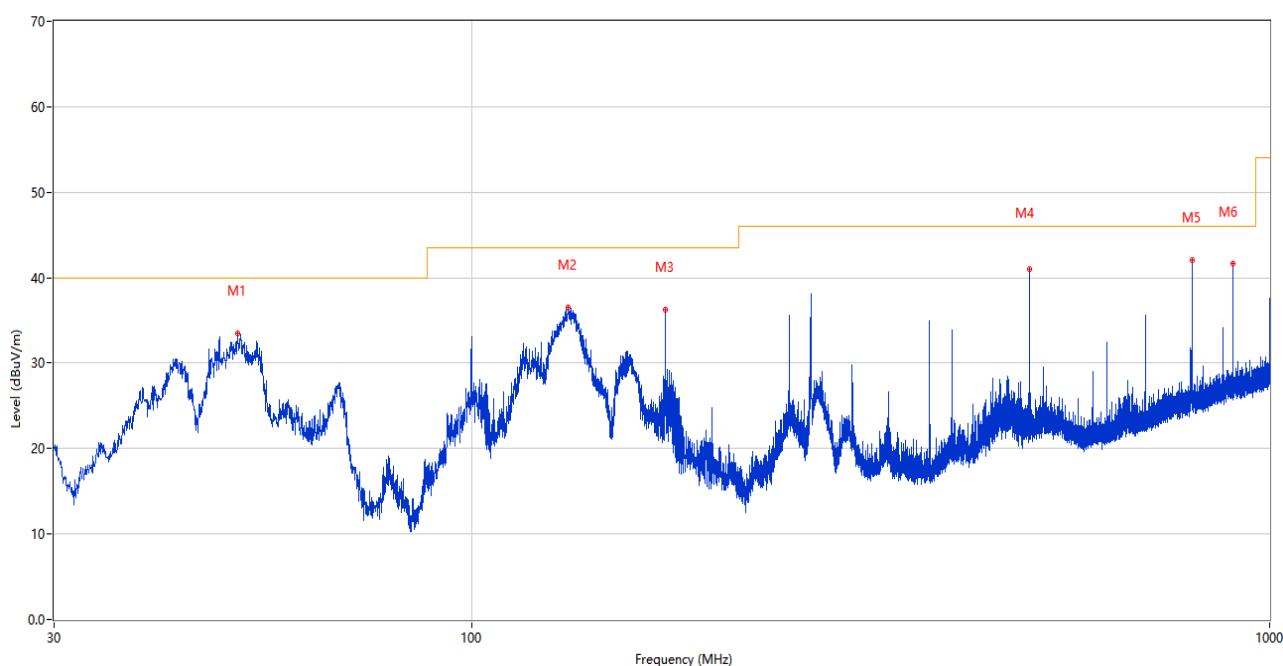
Note 1: For the test data above 1 GHz, according the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Note 2: The Radiated Emission is required to be investigated to the upper frequency of 5th harmonic of the highest internal frequency of EUT or 40 GHz, whichever is lower. The test results above 18GHz are only noise and are not recorded in the report.

Sample No.	S13	Temperature	22.1℃
Humidity	58%RH	Pressure	101kPa
Test Engineer	Chen Jingran	Test Date	2025.07.22

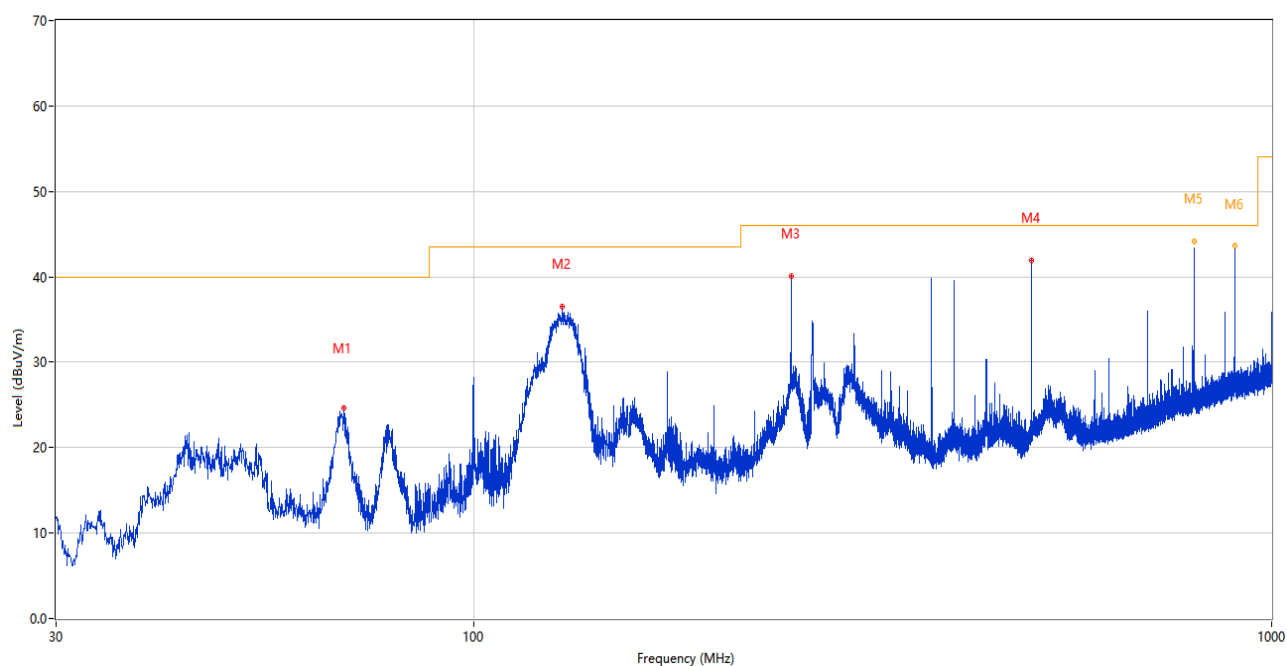
Test Mode 2

1) Test Antenna Vertical, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	50.952	33.48	-24.60	40.0	6.52	Peak	196.00	100	Vertical	Pass
2	132.238	36.56	-30.08	43.5	6.94	Peak	59.00	100	Vertical	Pass
3	175.015	36.23	-28.64	43.5	7.27	Peak	172.00	100	Vertical	Pass
4	500.014	40.96	-18.82	46.0	5.04	Peak	210.00	100	Vertical	Pass
5	799.986	42.03	-11.78	46.0	3.97	Peak	327.00	100	Vertical	Pass
6	899.993	41.63	-9.86	46.0	4.37	Peak	104.00	100	Vertical	Pass

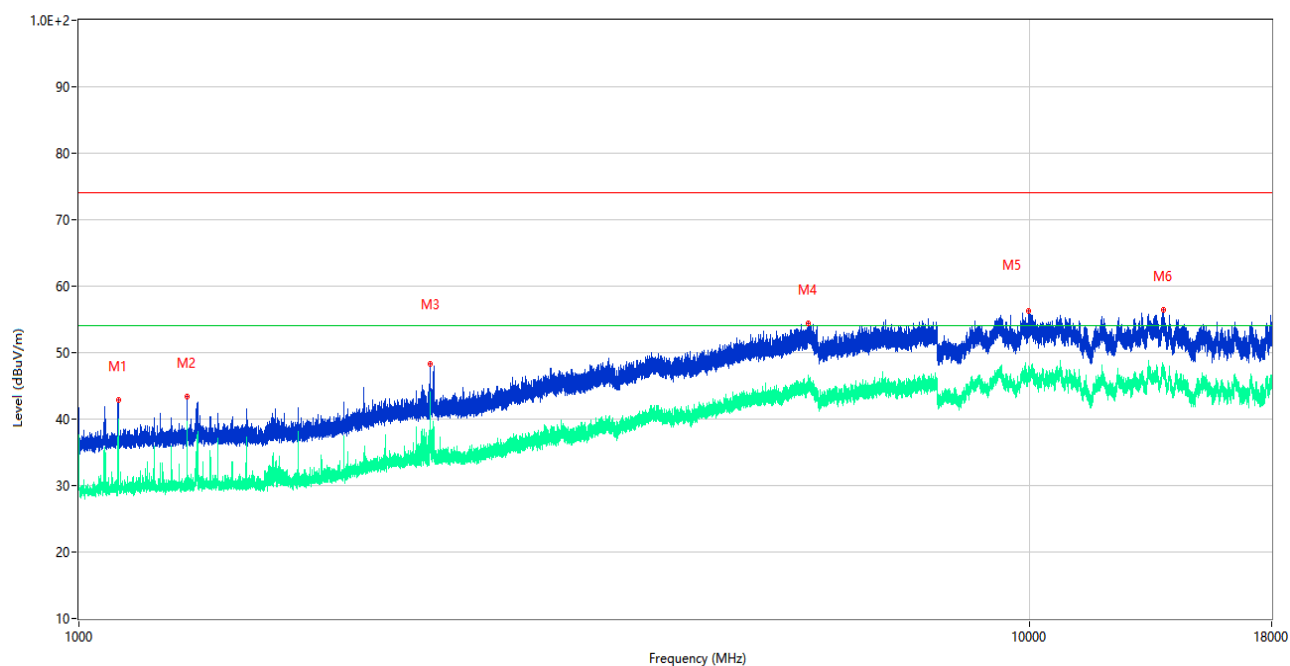
2) Test Antenna Horizontal, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	68.752	24.64	-28.74	40.0	15.36	Peak	135.00	200	Horizontal	Pass
2	129.279	36.50	-29.92	43.5	7.00	Peak	139.00	200	Horizontal	Pass
3	249.996	40.07	-25.16	46.0	5.93	Peak	360.00	100	Horizontal	Pass
4	500.014	41.96	-18.82	46.0	4.04	Peak	94.00	100	Horizontal	Pass
5	799.979	44.92	-11.78	46.0	1.08	Peak	264.00	111	Horizontal	N/A
5*	799.979	44.18	-11.78	46.0	1.82	QP	264.00	111	Horizontal	Pass
6	899.976	44.06	-9.86	46.0	1.94	Peak	290.00	100	Horizontal	N/A
6*	899.976	43.59	-9.86	46.0	2.41	QP	290.00	100	Horizontal	Pass

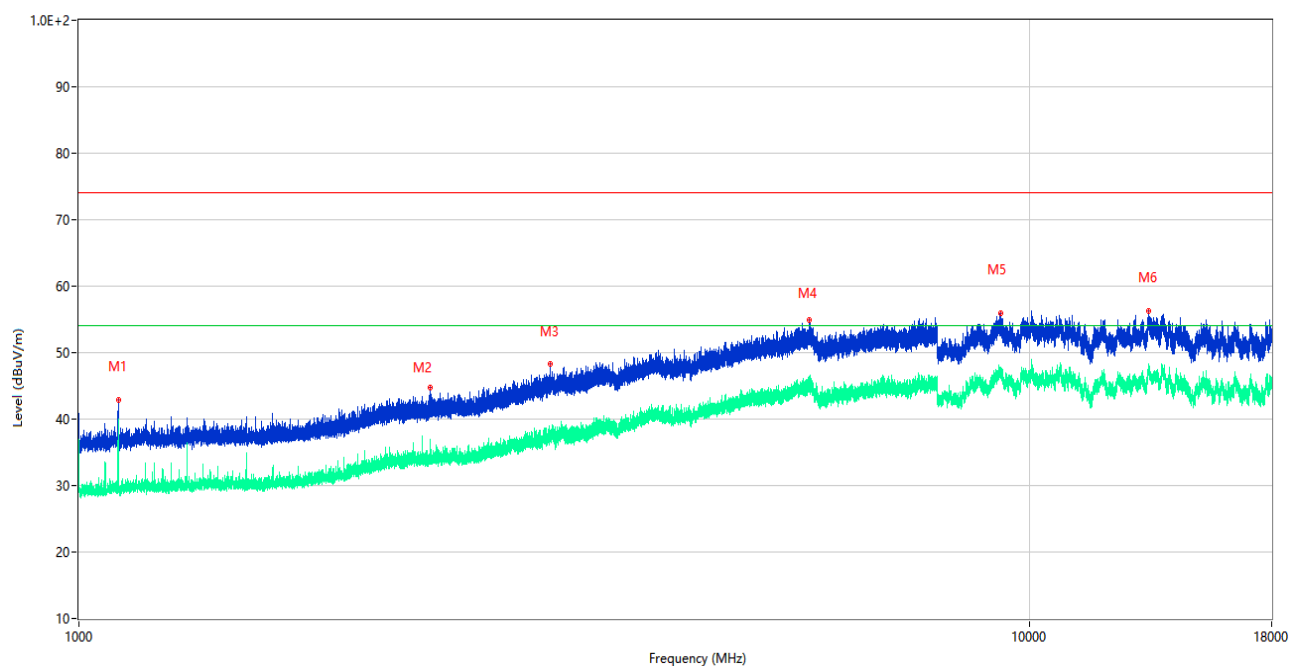
Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Below 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330120	2024.08.01	2025.07.31	☒
Amplifier (30-1GHz)	COM-MV	ZT30-1000M	B2017119081	2024.11.28	2025.11.27	☒
Test Antenna- Bi-Log	SCHWARZB ECK	VULB 9168	9168-00883	2025.03.23	2028.03.22	☒
Anechoic Chamber (#2)	YiHeng	9m*6m*6m	142	2024.07.21	2027.07.20	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.930	/		☒

3) Test Antenna Vertical, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1099.970	42.90	-15.65	74.0	31.10	Peak	167.00	100	Vertical	Pass
1**	1099.970	39.31	-15.65	54.0	14.69	AV	167.00	100	Vertical	Pass
2	1299.910	43.43	-15.38	74.0	30.57	Peak	223.00	100	Vertical	Pass
2**	1299.910	39.19	-15.38	54.0	14.81	AV	223.00	100	Vertical	Pass
3	2342.250	48.22	-11.11	74.0	25.78	Peak	337.00	100	Vertical	Pass
3**	2342.250	43.86	-11.11	54.0	10.14	AV	337.00	100	Vertical	Pass
4	5852.800	54.49	2.86	74.0	19.51	Peak	147.00	100	Vertical	Pass
4**	5852.800	45.08	2.86	54.0	8.92	AV	147.00	100	Vertical	Pass
5	9994.500	56.28	3.24	74.0	17.72	Peak	25.00	100	Vertical	Pass
5**	9994.500	47.06	3.24	54.0	6.94	AV	25.00	100	Vertical	Pass
6	13845.500	56.49	5.34	74.0	17.51	Peak	38.00	100	Vertical	Pass
6**	13845.500	47.44	5.34	54.0	6.56	AV	38.00	100	Vertical	Pass

4) Test Antenna Horizontal, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1100.230	42.90	-15.65	74.0	31.10	Peak	296.00	100	Horizontal	Pass
1**	1100.230	39.08	-15.65	54.0	14.92	AV	296.00	100	Horizontal	Pass
2	2341.730	44.70	-11.10	74.0	29.30	Peak	360.00	100	Horizontal	Pass
2**	2341.730	34.92	-11.10	54.0	19.08	AV	360.00	100	Horizontal	Pass
3	3137.070	48.29	-5.59	74.0	25.71	Peak	343.00	100	Horizontal	Pass
3**	3137.070	37.62	-5.59	54.0	16.38	AV	343.00	100	Horizontal	Pass
4	5870.620	54.89	2.77	74.0	19.11	Peak	94.00	100	Horizontal	Pass
4**	5870.620	46.00	2.77	54.0	8.00	AV	94.00	100	Horizontal	Pass
5	9331.500	55.89	4.55	74.0	18.11	Peak	84.00	100	Horizontal	Pass
5**	9331.500	47.81	4.55	54.0	6.19	AV	84.00	100	Horizontal	Pass
6	13364.000	56.32	5.12	74.0	17.68	Peak	296.00	100	Horizontal	Pass
6**	13364.000	47.14	5.12	54.0	6.86	AV	296.00	100	Horizontal	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Above 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330120	2024.08.01	2025.07.31	☒
Amplifier (1-12GHz)	Advanced Microwave	WLA652A	1740103	2024.11.28	2025.11.27	☒
Amplifier (0.8-21GHz)	Mini-Circuits	ZVA-213-S+	225321316	2024.11.28	2025.11.27	☒
Test Antenna- Horn	SCHWARZB ECK	BBHA 9120D	01917	2025.05.20	2028.05.19	☒
Anechoic Chamber (#2)	YiHeng	9m*6m*6m	142	2024.07.21	2027.07.20	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.930	/		☒

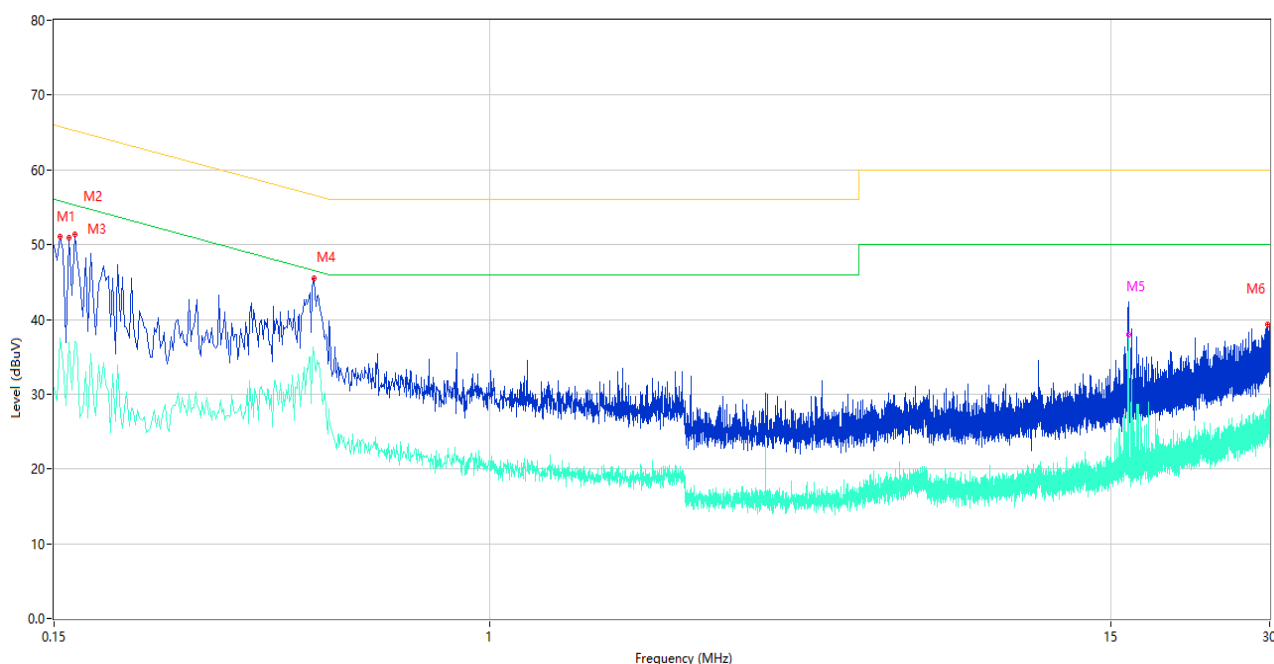
A.2 Conducted Emission, AC Ports

Note: Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. So, The configuration 120 VAC, 60 Hz and 240 VAC, 50 Hz were tested respectively, but only the worst configuration (120 VAC, 60 Hz) shown here.

Sample No.	S13	Temperature	22.1℃
Humidity	58%RH	Pressure	101kPa
Test Engineer	Yang Panxia	Test Date	2025.07.15

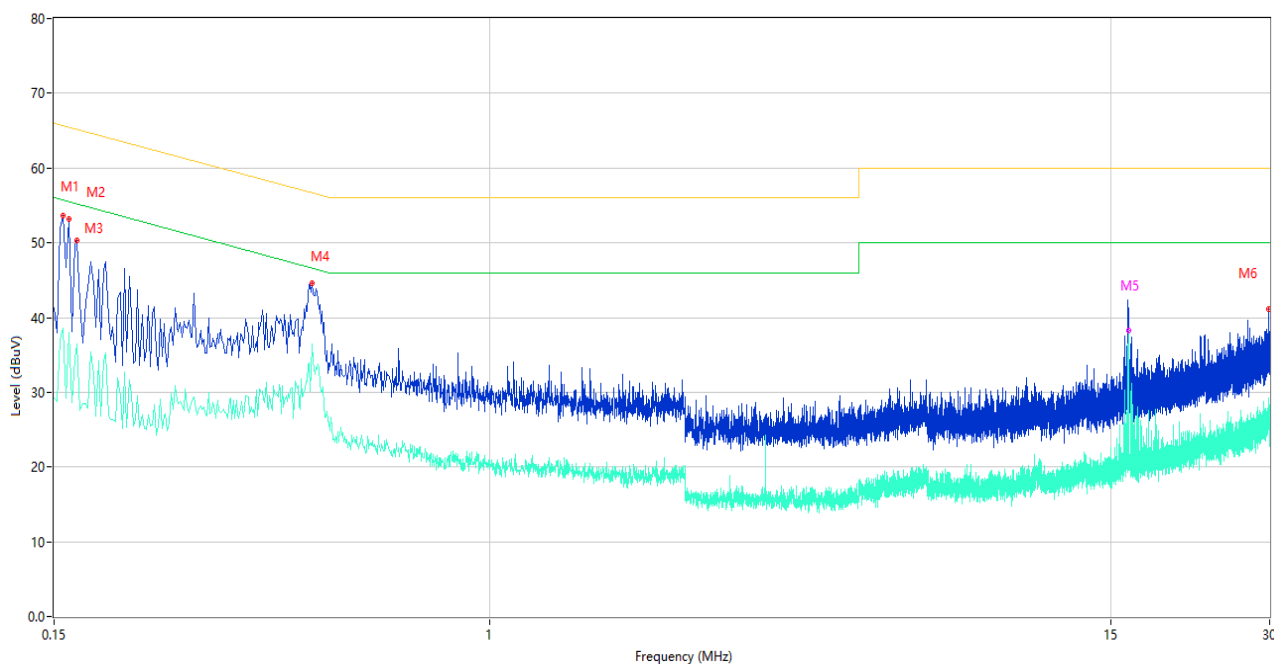
Test Mode 2

1) AC Ports - L Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.154	51.02	10.12	65.78	14.76	Peak	L	Pass
1**	0.154	37.52	10.12	55.78	18.26	AV	L	Pass
2	0.160	50.95	10.10	65.46	14.51	Peak	L	Pass
2**	0.160	36.85	10.10	55.46	18.61	AV	L	Pass
3	0.164	51.43	10.09	65.26	13.83	Peak	L	Pass
3**	0.164	37.09	10.09	55.26	18.17	AV	L	Pass
4	0.466	45.45	10.47	56.58	11.13	Peak	L	Pass
4**	0.466	35.22	10.47	46.58	11.36	AV	L	Pass
5	16.226	42.31	13.80	60.00	17.69	Peak	L	Pass
5**	16.226	38.02	13.80	50.00	11.98	AV	L	Pass
6	29.758	39.39	17.34	60.00	20.61	Peak	L	Pass
6**	29.758	28.24	17.34	50.00	21.76	AV	L	Pass

2) AC Ports - N Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.156	53.65	10.11	65.67	12.02	Peak	N	Pass
1**	0.156	38.58	10.11	55.67	17.09	AV	N	Pass
2	0.160	53.15	10.10	65.46	12.31	Peak	N	Pass
2**	0.160	37.90	10.10	55.46	17.56	AV	N	Pass
3	0.166	50.27	10.08	65.16	14.89	Peak	N	Pass
3**	0.166	36.42	10.08	55.16	18.74	AV	N	Pass
4	0.462	44.60	10.49	56.66	12.06	Peak	N	Pass
4**	0.462	36.43	10.49	46.66	10.23	AV	N	Pass
5	16.228	41.22	13.80	60.00	18.78	Peak	N	Pass
5**	16.228	38.23	13.80	50.00	11.77	AV	N	Pass
6	29.836	41.17	17.11	60.00	18.83	Peak	N	Pass
6**	29.836	28.19	17.11	50.00	21.81	AV	N	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	KEYSIGHT	N9010B	MY57110309	2024.08.01	2025.07.31	☒
LISN	SCHWARZB ECK	NSLK 8127	8127-687	2025.04.29	2026.04.28	☒
ISN	TESEQ	ISN T800	34449	2024.11.06	2025.11.05	☐
ISN	TESEQ	ISN T8-Cat6	53561	2025.06.01	2026.05.31	☐
Shielded Room	YiHeng Electronic Co., Ltd	3.5m*3.1m*2. 8m	112	2025.02.14	2028.02.13	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.930	/		☒

ANNEX B TEST SETUP PHOTOS

Please refer the document “BL-SZ2570530-AE.PDF”.

ANNEX C EUT EXTERNAL PHOTOS

Please refer the document “BL-SZ2570530-AW.PDF”.

ANNEX D EUT INTERNAL PHOTOS

Please refer the document “BL-SZ2570530-AI.PDF”.

Statement

1. The laboratory guarantees the scientificity, accuracy and impartiality of the test, and is responsible for all the information in the report, except the information provided by the customer. The customer is responsible for the impact of the information provided on the validity of the results.
2. The report without China inspection body and laboratory Mandatory Approval (CMA) mark has no effect of proving to the society.
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4. This report is invalid if it is altered, without the signature of the testing and approval personnel, or without the "inspection and testing dedicated stamp" or test report stamp.
5. The test data and results are only valid for the tested samples provided by the customer.
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--END OF REPORT--